
AMLCDs WITH INTEGRATED SCANNERS

Thursday, May 24 / 10:40 am - 11:40 am / Ballroom A

Chair:

Norbert Fruehauf, University of Stuttgart, Stuttgart, Germany

Co-Chair:

Roger G. Stewart, Sourland Mountain Associates, Morgan Hill, CA, U.S.A.

46.1: Invited Paper: Integrated a-Si:H TFT Gate Driver Circuits on Large-Area TFT-LCDs (10:40)

S-H. Moon, Y-S. Lee, M-C. Lee, N-D. Kim, S-S. Kim
Samsung Electronics Co., Ltd., Chungcheongnam-do, Korea

Integrated a-Si:H TFT gate driver circuits on large-area TFT-LCDs will be reviewed. An implementation of novel ac-biased holding circuits to overcome the driver instability is proposed. The reliability tests verified that the proposed a-Si:H TFT gate drivers showed a high reliability.

46.2: Invited Paper: High-Performance LTPS Technologies for Advanced Mobile-Display Applications (11:00)

H. Ohshima, M. Führen
Toppoly Optoelectronics Corp., Miao-Li County, Taiwan, ROC

Innovations underlining the unique capability of LTPS TFT technologies will be provided. Integrated ambient-light sensing, system-on-panel integration, ultra-low-standby-power memory-in-pixel, advanced driving schemes, pixel designs for wide viewing, and high-performance AMOLEDs will be highlighted.

46.3: DRAM-Frame-Memory Embedded SOG LCD (11:20)

H. Haga, Y. Nonaka, Y. Kamon, Y. Kitagishi, M. Jumonji,
K. Takatori, H. Asada
NEC LCD Technologies, Ltd., Kanagawa, Japan

An SOG LCD with an integrated 230-kbit DRAM frame memory has been demonstrated. To achieve this level of integration, a memory system architecture for an horizontal stripe design was developed. Memory tests performed on still and moving images were displayed.

LUNCH (11:40–2:00)**AUTHOR INTERVIEWS (5:00–6:00)**